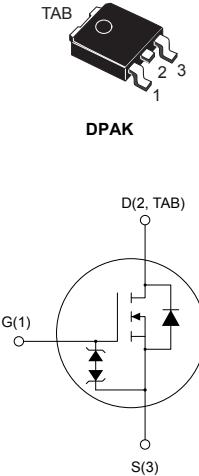


### N-channel 650 V, 132 mΩ typ., 20 A MDmesh M9 Power MOSFET in a DPAK package

#### Features



AM01476v1\_tab

Order code	V <sub>DS</sub>	R <sub>DS(on)</sub> max.	I <sub>D</sub>
STD65N160M9	650 V	160 mΩ	20 A

- Worldwide best FOM R<sub>DS(on)</sub>\*Q<sub>g</sub> among silicon-based devices
- Higher V<sub>DSS</sub> rating
- Higher dv/dt capability
- Excellent switching performance
- Easy to drive
- 100% avalanche tested
- Zener-protected

#### Applications

- High efficiency switching applications

#### Description

This N-channel Power MOSFET is based on the most innovative super-junction MDmesh M9 technology, suitable for medium/high voltage MOSFETs featuring very low R<sub>DS(on)</sub> per area. The silicon based M9 technology benefits from a multi-drain manufacturing process which allows an enhanced device structure. The resulting product has one of the lower on-resistance and reduced gate charge values, among all silicon based fast switching super-junction Power MOSFETs, making it particularly suitable for applications that require superior power density and outstanding efficiency.



#### Product status link

[STD65N160M9](#)

#### Product summary

Order code	STD65N160M9
Marking	65N160M9
Package	DPAK
Packing	Tape and reel

## 1 Electrical ratings

**Table 1. Absolute maximum ratings**

Symbol	Parameter	Value	Unit
$V_{GS}$	Gate-source voltage	$\pm 30$	V
$I_D^{(1)}$	Drain current (continuous) at $T_C = 25^\circ\text{C}$	20	A
	Drain current (continuous) at $T_C = 100^\circ\text{C}$	12.5	
$I_{DM}^{(2)}$	Drain current (pulsed)	60	A
$P_{TOT}$	Total power dissipation at $T_C = 25^\circ\text{C}$	106	W
$dv/dt^{(3)}$	Peak diode recovery voltage slope	50	V/ns
$di/dt^{(3)}$	Peak diode recovery current slope	900	A/ $\mu\text{s}$
$dv/dt^{(4)}$	MOSFET dv/dt ruggedness	120	V/ns
$T_{stg}$	Storage temperature range	-55 to 150	$^\circ\text{C}$
$T_J$	Operating junction temperature range		$^\circ\text{C}$

1. Referred to TO-220 package.
2. Pulse width is limited by safe operating area.
3.  $I_{SD} \leq 10 \text{ A}$ ,  $V_{DS} (\text{peak}) < V_{(BR)DSS}$ ,  $V_{DD} \leq 400 \text{ V}$ .
4.  $V_{DS} (\text{peak}) < V_{(BR)DSS}$ ,  $V_{DD} \leq 400 \text{ V}$ .

**Table 2. Thermal data**

Symbol	Parameter	Value	Unit
$R_{thJC}$	Thermal resistance, junction-to-case	1.18	$^\circ\text{C}/\text{W}$
$R_{thJA}^{(1)}$	Thermal resistance, junction-to-ambient	50	$^\circ\text{C}/\text{W}$

1. When mounted on 1 inch<sup>2</sup> FR-4, 2 Oz copper board.

**Table 3. Avalanche characteristics**

Symbol	Parameter	Value	Unit
$I_{AR}$	Avalanche current, repetitive or non-repetitive (pulse width limited by $T_J$ max)	4	A
$E_{AS}$	Single pulse avalanche energy (starting $T_J = 25^\circ\text{C}$ , $I_D = I_{AR}$ , $V_{DD} = 50 \text{ V}$ )	200	mJ

## 2 Electrical characteristics

$T_C = 25^\circ\text{C}$  unless otherwise specified.

**Table 4. On/off states**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(\text{BR})\text{DSS}}$	Drain-source breakdown voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$	650			V
$I_{\text{DSS}}$	Zero gate voltage drain current	$V_{GS} = 0 \text{ V}, V_{DS} = 650 \text{ V}$		1		$\mu\text{A}$
		$V_{GS} = 0 \text{ V}, V_{DS} = 650 \text{ V}, T_C = 125^\circ\text{C}$ <sup>(1)</sup>		200		
$I_{\text{GSS}}$	Gate-body leakage current	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 25 \text{ V}$			$\pm 5$	$\mu\text{A}$
$V_{GS(\text{th})}$	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	3.2	3.7	4.2	V
$R_{\text{DS(on)}}$	Static drain-source on-resistance	$V_{GS} = 10 \text{ V}, I_D = 10 \text{ A}$		132	160	$\text{m}\Omega$

1. Specified by design, not tested in production.

**Table 5. Dynamic**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$C_{iss}$	Input capacitance	$V_{DS} = 400 \text{ V}, f = 1 \text{ MHz}, V_{GS} = 0 \text{ V}$	-	1240	-	pF
$C_{oss}$	Output capacitance		-	25	-	pF
$C_{oss \text{ eq.}}^{(1)}$	Equivalent output capacitance	$V_{DS} = 0 \text{ to } 400 \text{ V}, V_{GS} = 0 \text{ V}$	-	290	-	pF
$R_G$	Intrinsic gate resistance	$f = 1 \text{ MHz}, I_D = 0 \text{ A}$	-	2	-	$\Omega$
$Q_g$	Total gate charge	$V_{DD} = 400 \text{ V}, I_D = 10 \text{ A}, V_{GS} = 0 \text{ to } 10 \text{ V}$ (see Figure 14. Test circuit for gate charge behavior)	-	32	-	nC
$Q_{gs}$	Gate-source charge		-	7	-	nC
$Q_{gd}$	Gate-drain charge		-	15	-	nC

1.  $C_{oss \text{ eq.}}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to stated value.

**Table 6. Switching times**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 325 \text{ V}, I_D = 10 \text{ A}, R_G = 4.7 \Omega, V_{GS} = 10 \text{ V}$ (see Figure 13. Test circuit for resistive load switching times and Figure 18. Switching time waveform)	-	13	-	ns
$t_r$	Rise time		-	5	-	ns
$t_{d(off)}$	Turn-off delay time		-	42	-	ns
$t_f$	Fall time		-	6	-	ns

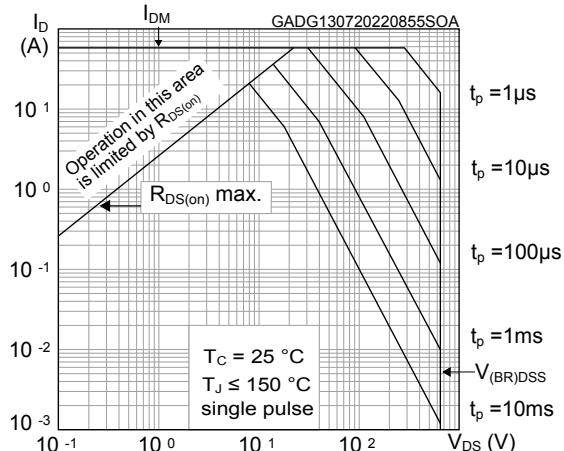
**Table 7. Source-drain diode**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$I_{SD}^{(1)}$	Source-drain current		-		20	A
$I_{SDM}^{(2)}$	Source-drain current (pulsed)		-		60	A
$V_{SD}^{(3)}$	Forward on voltage	$I_{SD} = 20 \text{ A}$ , $V_{GS} = 0 \text{ V}$	-		1.6	V
$t_{rr}$	Reverse recovery time	$I_{SD} = 20 \text{ A}$ , $dI/dt = 100 \text{ A}/\mu\text{s}$ ,	-	192		ns
$Q_{rr}$	Reverse recovery charge	$V_{DD} = 100 \text{ V}$	-	1.8		$\mu\text{C}$
$I_{RRM}$	Reverse recovery current	(see Figure 15. Test circuit for inductive load switching and diode recovery times)	-	17.5		A
$t_{rr}$	Reverse recovery time	$I_{SD} = 20 \text{ A}$ , $dI/dt = 100 \text{ A}/\mu\text{s}$ ,	-	280		ns
$Q_{rr}$	Reverse recovery charge	$V_{DD} = 100 \text{ V}$ , $T_J = 150 \text{ }^\circ\text{C}$	-	3.6		$\mu\text{C}$
$I_{RRM}$	Reverse recovery current	(see Figure 15. Test circuit for inductive load switching and diode recovery times)	-	20.5		A

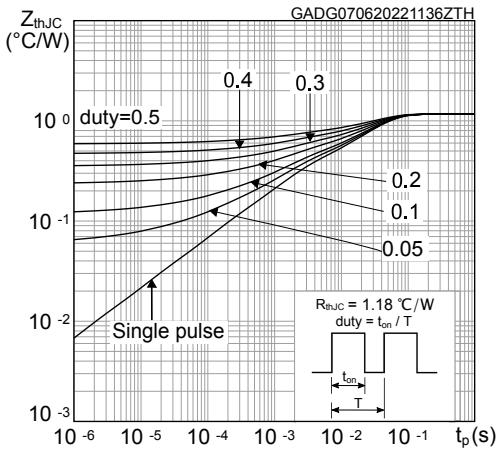
1. Referred to TO-220 package.
2. Pulse width is limited by safe operating area.
3. Pulsed: pulse duration = 300  $\mu\text{s}$ , duty cycle 1.5%.

## 2.1 Electrical characteristics (curves)

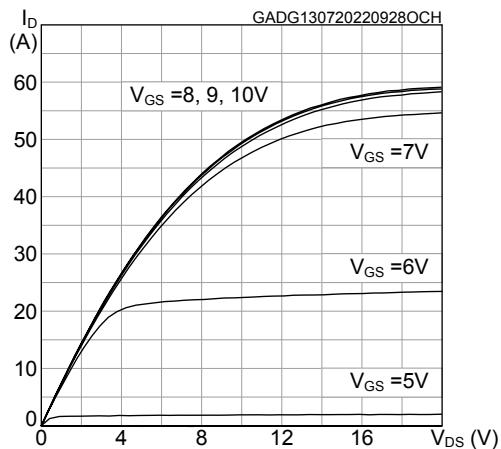
**Figure 1. Safe operating area**



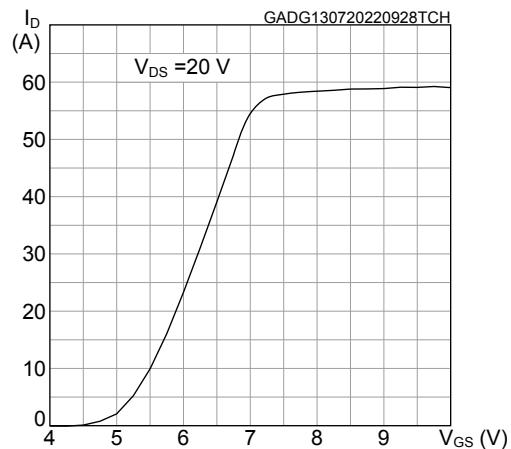
**Figure 2. Maximum transient thermal impedance**



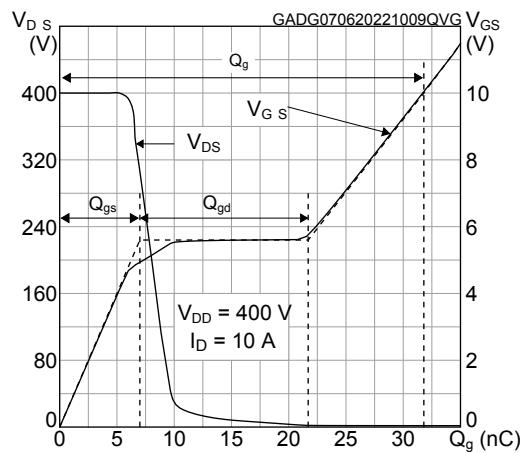
**Figure 3. Typical output characteristics**



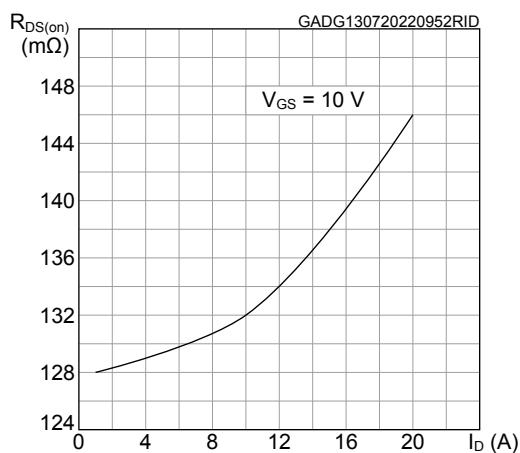
**Figure 4. Typical transfer characteristics**

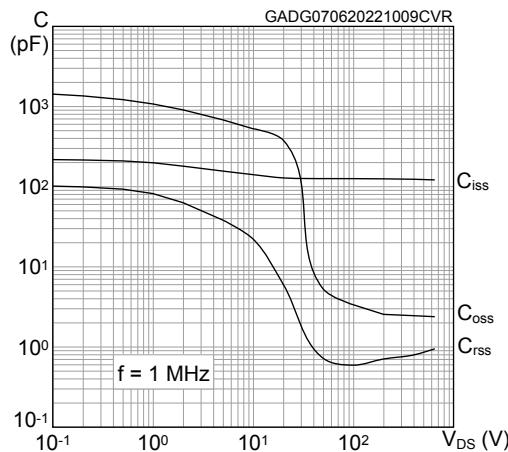
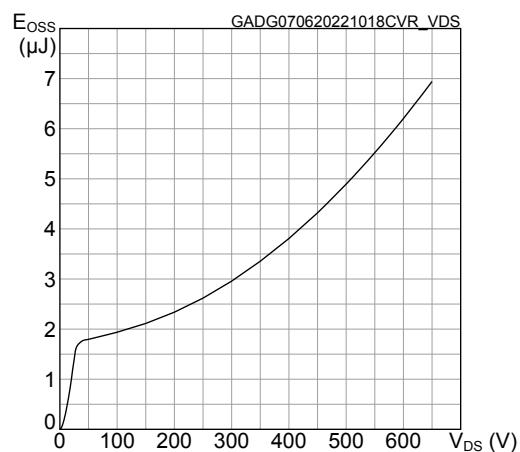
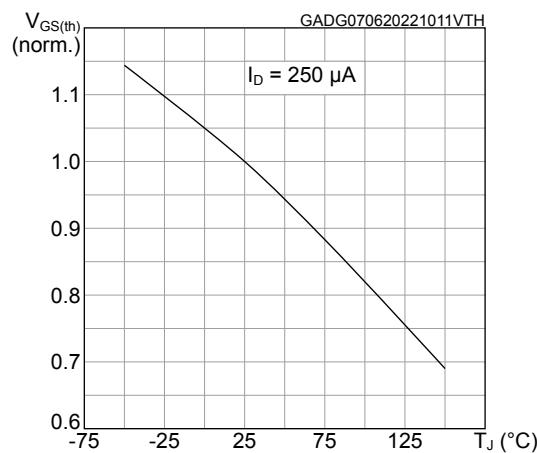
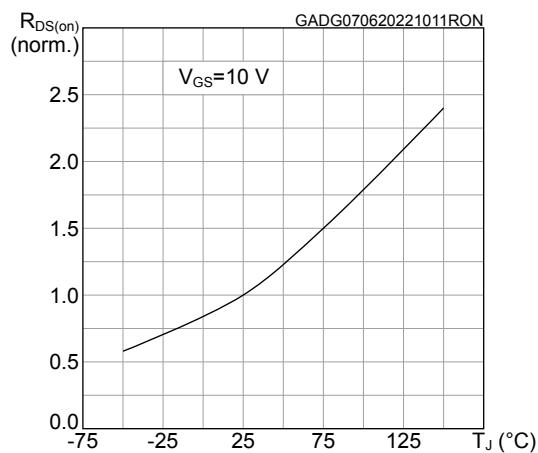
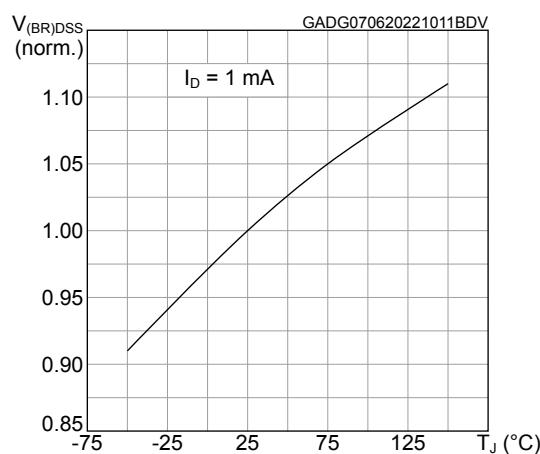
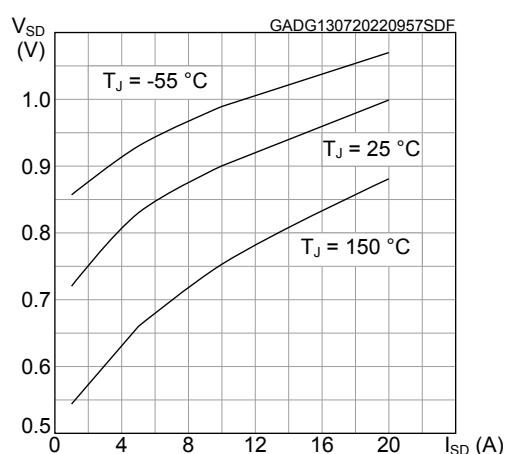


**Figure 5. Typical gate charge characteristics**



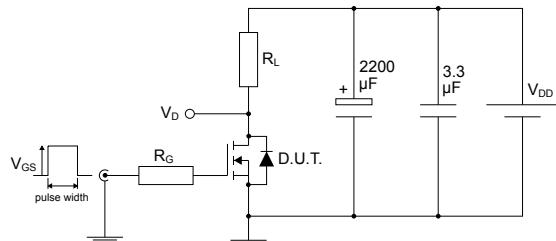
**Figure 6. Typical drain-source on-resistance**



**Figure 7. Typical capacitance characteristics**

**Figure 8. Typical output capacitance stored energy**

**Figure 9. Normalized gate threshold vs temperature**

**Figure 10. Normalized on-resistance vs temperature**

**Figure 11. Normalized breakdown voltage vs temperature**

**Figure 12. Typical reverse diode forward characteristics**


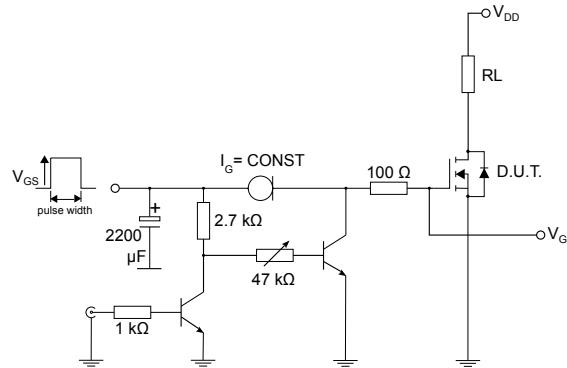
### 3 Test circuits

**Figure 13.** Test circuit for resistive load switching times



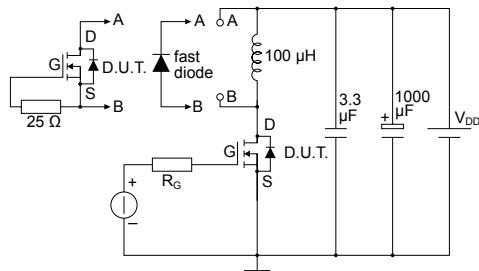
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**Figure 14.** Test circuit for gate charge behavior



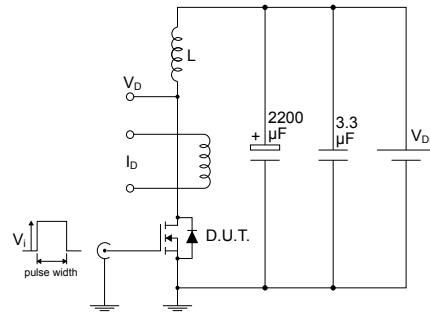
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**Figure 15.** Test circuit for inductive load switching and diode recovery times



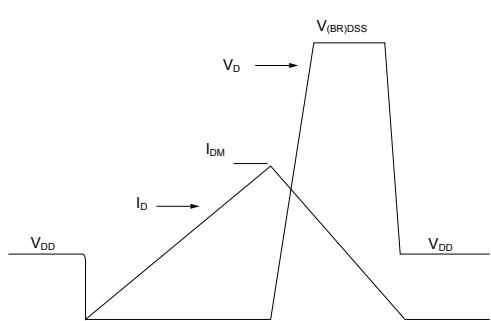
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**Figure 16.** Unclamped inductive load test circuit



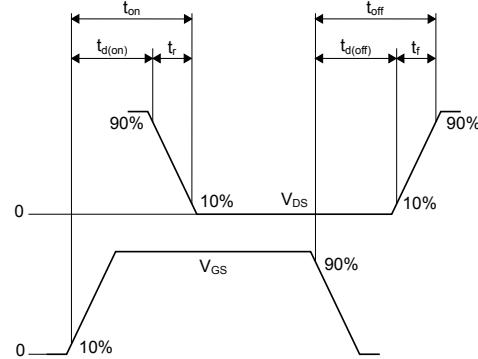
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**Figure 17.** Unclamped inductive waveform



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**Figure 18.** Switching time waveform



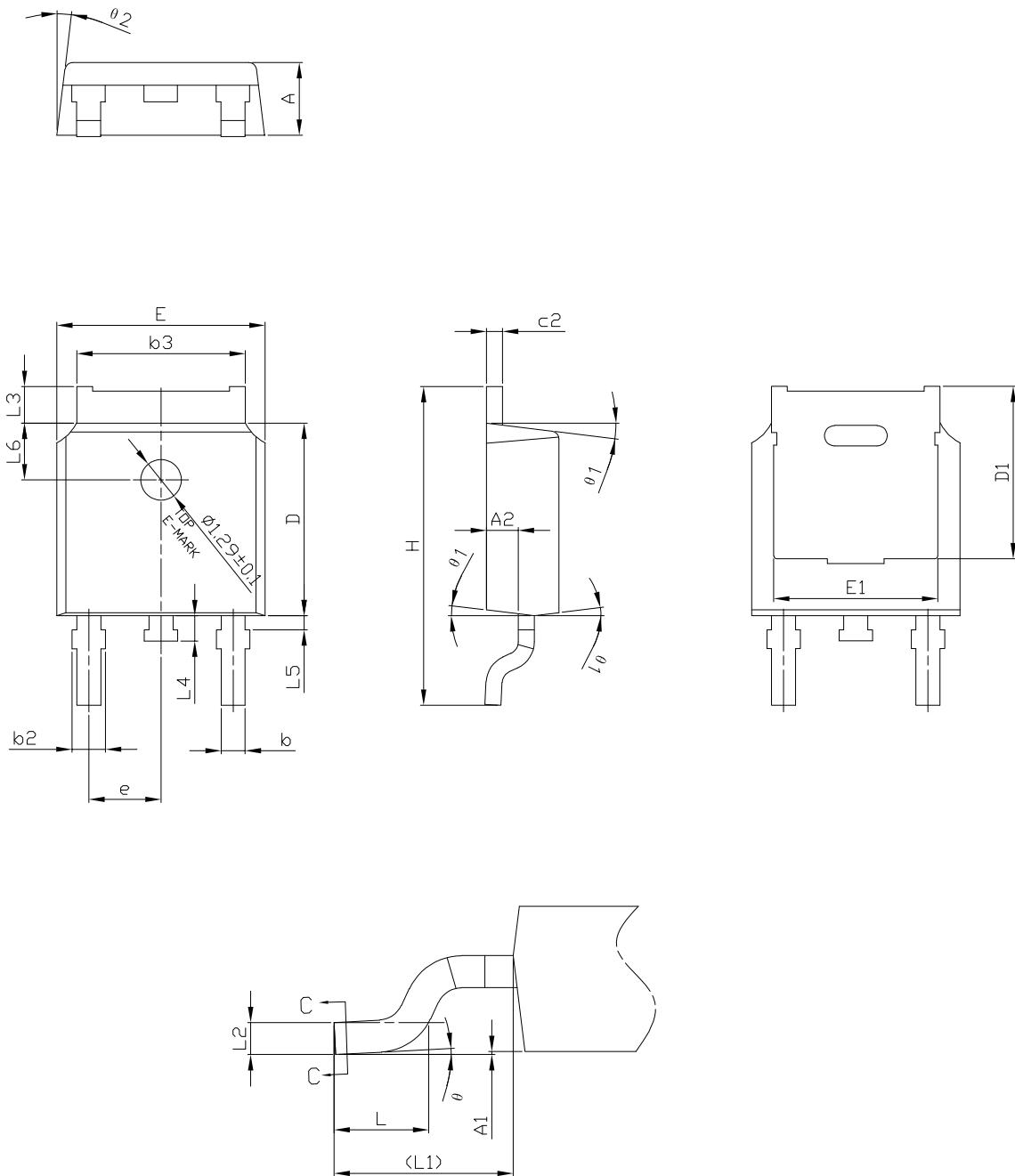
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## 4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com). ECOPACK is an ST trademark.

### 4.1 DPAK (TO-252) type C3 package information

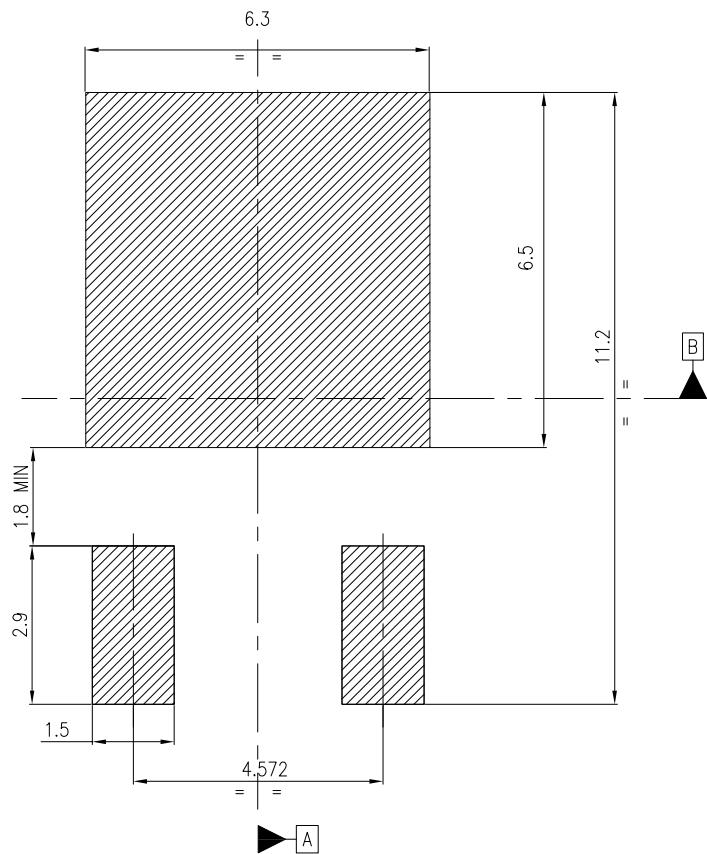
Figure 19. DPAK (TO-252) type C3 package outline



0068772\_type-C3\_rev34

Table 8. DPAK (TO-252) type C3 mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	2.20	2.30	2.38
A1	0.00		0.10
A2	0.90	1.01	1.10
b	0.72		0.85
b2	0.72		1.10
b3	5.13	5.33	5.46
c	0.47		0.60
c2	0.47		0.60
D	6.00	6.10	6.20
D1	5.20	5.45	5.70
E	6.50	6.60	6.70
E1	5.00	5.20	5.40
e	2.186	2.286	2.386
H	9.80	10.10	10.40
L	1.40	1.50	1.70
L1	2.90 REF		
L2	0.51 BSC		
L3	0.90		1.25
L4	0.60	0.80	1.00
L5	0.15		0.75
L6	1.80 REF		
θ	0°		8°
θ1	5°	7°	9°
θ2	5°	7°	9°

**Figure 20. DPAK (TO-252) recommended footprint (dimensions are in mm)**

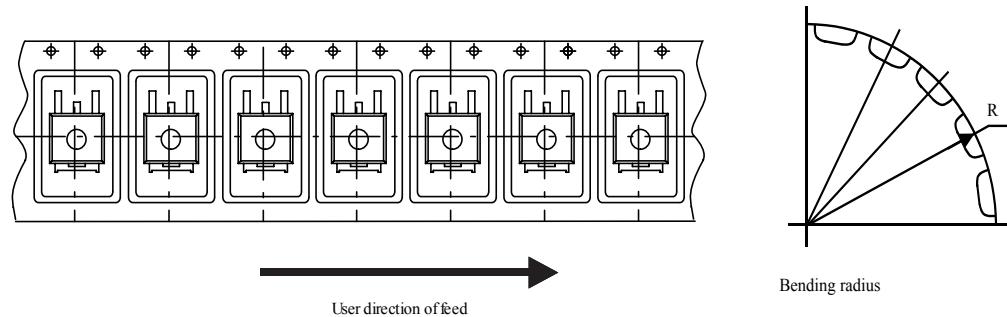
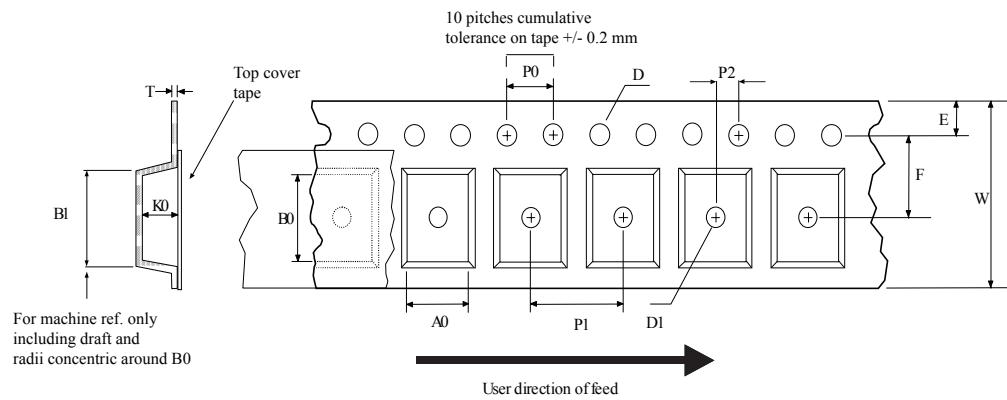
## Notes:

- 1) This footprint is able to ensure insulation up to 630 Vrms (according to CEI IEC 664-1)
- 2) The device must be positioned within  $\Phi | 0.05 | A | B$

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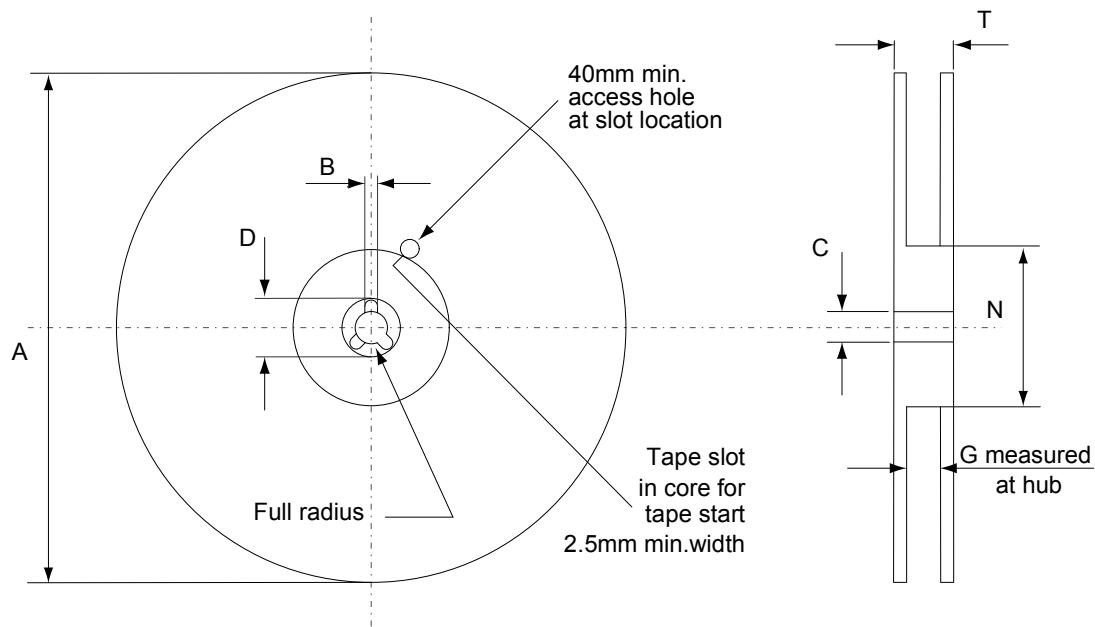
## 4.2 DPAK (TO-252) packing information

**Figure 21. DPAK (TO-252) tape outline**



AM08852v1

Figure 22. DPAK (TO-252) reel outline



AM06038v1

Table 9. DPAK (TO-252) tape and reel mechanical data

Tape			Reel		
Dim.	mm		Dim.	mm	
	Min.	Max.		Min.	Max.
A0	6.8	7	A		330
B0	10.4	10.6	B	1.5	
B1		12.1	C	12.8	13.2
D	1.5	1.6	D	20.2	
D1	1.5		G	16.4	18.4
E	1.65	1.85	N	50	
F	7.4	7.6	T		22.4
K0	2.55	2.75			
P0	3.9	4.1	Base qty.		2500
P1	7.9	8.1	Bulk qty.		2500
P2	1.9	2.1			
R	40				
T	0.25	0.35			
W	15.7	16.3			

## Revision history

**Table 10. Document revision history**

Date	Revision	Changes
13-Jul-2022	1	First release.
01-Dec-2022	2	Updated title in cover page. Updated <i>Features</i> in cover page. Updated <i>Table 1. Absolute maximum ratings</i> . Updated <i>Table 5. Dynamic</i> . Updated <i>Table 7. Source-drain diode</i> . Updated <i>Figure 3. Typical output characteristics</i> .
31-May-2023	3	Updated <i>Table 6. Switching times</i> . Updated <i>Section 3 Test circuits</i> . Updated <i>Section 4.1 DPAK (TO-252) type C3 package information</i> .

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